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(54) TOP-DOWN RELATIVE DAC CALIBRATION

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(57)ABSTRACT

A system and method for calibrating a digital-to-analog converter (DAC) device. The method includes tuning a second subset of one or more DAC segments to match a strength of a first subset of DAC segments wherein the first subset of DAC segments is of a strength nominally equal to that of the second subset of DAC segments. The process is iterative, and the second subset of DAC segments is associated with lesser significant bits than the bits associated with the first subset of DAC segments. The process is repeated to tune each of successive second subsets of DAC segments to corresponding successive first subsets of DAC segments in top-down order from a segment associated with a MSB input to a segment associated with a LSB input. In each case the first subset of DAC segments is of a strength nominally equal to that of the second subset of DAC segments.

